

| | | |
|---|--|---|
| Search Notes  | Application/Control No. 10/632,554 | Applicant(s)/Patent under Reexamination TAKANO ET AL. |
| Examiner Shih-wen Hsieh | Art Unit 2861 | |

| INTERFERENCE SEARCHED | | | |
|-----------------------|----------|-----------|----------|
| Class | Subclass | Date | Examiner |
| 347 | 37,8 | 8/16/2005 | SWH |
| 400 | 59 | 8/16/2005 | SWH |
| | | | |
| | | | |